

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: SHIBATA, et al.

Serial No.: Not yet assigned

Filed: November 4, 2003

For: METHOD AND APPARATUS FOR INSPECTING DEFECTS

INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR 1.97 & 1.98

Mail Stop DD
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

November 4, 2003

Sir:

In the matter of the above-identified application, applicants are submitting herewith a copy of a communication from a foreign patent office in a counterpart foreign application and copies of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

This information disclosure statement is being submitted with the new application.



Although some of the documents listed on the attached form equivalent to Form PTO-1449 are not in the English language, the requirement of 37 CFR 1.98(a)(3) for a concise explanation of the relevance is satisfied by the discussion of the documents in the specification, for example, on page one (1).

It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Antonelli, Terry, Stout & Kraus Deposit Account No. 01-2135 (Case: 501.43163X00), and please credit any excess fees to such deposit account.

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS LLP


Melvin Kraus 
Registration No. ~~22,466~~
28,577

MK/alb
(703) 312-6600
Attachments

Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO. 501.43163X00	SERIAL NO.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		APPLICANT SHIBATA, et al.	
		FILING DATE November 4, 2003	GROUP

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
	AA					
	AB					
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FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Abstract	
						Yes	No
	AM	9-218165	08/19/1997	JP	G01N	21/88	X
	AN						
	AO						
	AP						
	AQ						
	AR						
	AS						
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	AU	
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Examiner		Date Considered